

Mid term examination, 100min., closed book, individual efforts

May 8, 2008

1. BJT

The NPN structure with $W_E = 0.2 \mu m$, $W_B = 0.1 \mu m$ and $W_C = 100 \mu m$ (or infinity).
 $N_{D,E} = 1.E20/cm^3$, $N_{A,B} = 5E18/cm^3$ and $N_{D,C} = 6E16/cm^3$ is biased with
 $V_{BE} = 0.7V$ and $V_{CE} = 3V$. $A_E = 1 \mu m^2$, V_t (thermal voltage) = $24mV$
 v_{sat} (saturation velocity of electron) = $1E7 cm/sec$ in the CB depletion region.

With this, it was found that the flux component at each point of emitter(E), base(B), and collector(C) are

$$\begin{aligned} F_{n,B}(0) &= 1.e23 /cm^2\text{-sec}; F_{n,B}(W_b) = 0.99 F_{n,B}(0) \\ F_{p,E}(0) &= 0.01 F_{n,B}(0); F_{p,E}(W_e) = 0.99 F_{p,E}(0) \\ F_{p,C}(0) &= 1.E17/cm^2\text{-sec} \end{aligned}$$

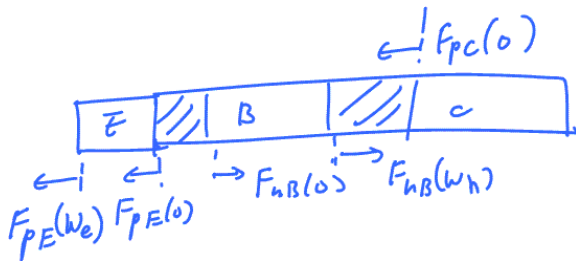


Fig. The flux density in each region of NPN BJT

b) Total recombination rates:

in the EB junction : $1e20/cm^2\text{-sec}$.

in the BC depletion layer is $-5E18/cm^2\text{-sec}$ (net generation)

c) After base push out occurs, I_c is proportional to $\exp(V_{BE}/2V_t)$.

A. General DC BJT characteristics

When $I_c = \beta \cdot I_E + I_{CBO}$

Find β , I_{CBO} , for the bias condition above.

B. Onset of the base push out

Find the critical collector current for the start of base widening. Also,

Find V_{BE} voltage for the critical collector current. (Hint. $J_{c0} = qN_{DC} v_{sat}$).

C. Plot transistor β , vs. I_c (roughly, I_c from $V_{BE} = 0.3V$ to $I_c = 10 \cdot I_{c0}$ (start of base push out))

D. BV_{ceo}

The BV_{cbo} is measured to be $7V$. Also, M in the BC junction can be written as

$$M = 1/(1-(V_{cb}/BV_{cbo})^{**4}).$$

Assume that in the case for base open, $V_{cb} \sim V_{ce}$.

1) Find I_{CEO} when $V_{CE}=6V$. (Assume I_{CBO} is same as the value a) above)

Here assume that transistor β , is same as the value in a) above.

Check the validity of this assumption using the data in D.

You measure the I_{CEO} vs. V_{CEO} as shown in fig. 1.

2) What is the estimated value for BV_{CEO} (Here assume that transistor β , is same as the value in a) above.)

3) Explain the reason for the negative resistance.

4) Estimate the I_{CEO} value from which BV_{CEO} increases again.

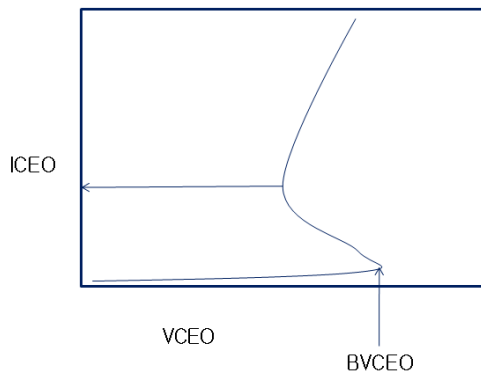


fig. 1. Measured I_{CEO} vs. V_{CEO} (assume that $V_{CEO}=V_{CBO}$)

2. MOSFET

Consider the gated PN junction structure as shown in fig. 2.

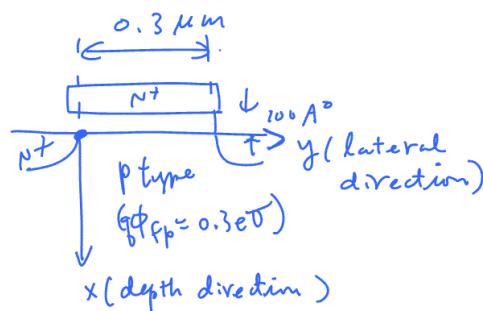
(N^+ polysilicon with $E_f=E_c$, P substrate with $N_a=1.E17/cm^2$ so that

$$q\phi_{fp}=0.3eV)$$

A. Draw the band diagram along x direction (including gate, oxide and P substrate)

when $V_S=0$, $V_B=-1V$ and $V_G=V_T$. (Denote the surface potential ϕ_s , E_{fn} , E_{fp} , E_i

in the figure)



B. Obtain the ϕ_s (surface potential) value when $V_G = V_T$. (Hint. Notice that V_T is when ϕ_s is $2 \pm \phi_p$ with respect to E_{fn} , not E_{fp}).

C. In the case for B, what is Q_{dmax} [C/cm²]? Express the answer in terms of i_s , N_A and other parameters.